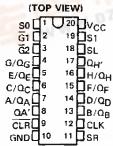
SN54LS323, SN74LS323 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

SDLS160

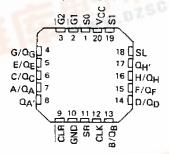
OCTOBER 1976 - REVISED MARCH 1988

- Multiplexed Inputs/Outputs Provide Improved Bit Density
- Four Modes of Operation:
 Hold (Store) Shift Left
 Shift Right Load Data
- Operates with Outputs Enabled or at High Z
- 3-State Outputs Drive Bus Lines Directly
- Can Be Cascaded for N-Bit Word Lengths
- Typical Power Dissipation . . . 175 mW
- Exceptionally Stable Shift (Clock)
 Frequency . . . 25 MHz
- Applications:
 Stacked or Push-Down Registers,
 Buffer Storage, and
 Accumulator Registers
- SN54LS299 and SN74LS299 Are Similar But Have Direct Overriding Clear

\$N54LS323 . . . J OR W PACKAGE \$N74LS323 . . . DW OR N PACKAGE



SN64LS323 . . . FK PACKAGE (TOP VIEW)



description

These Low-Power Schottky eight-bit universal registers feature multiplexed inputs/outputs to achieve full eight-bit data handling in a single 20-pin package. Two function-select inputs and two output-control inputs can be used to choose the modes of operation listed in the function table. Synchronous parallel loading is accomplished by taking both function-select lines, S0 and S1, high. This places the three-state outputs in a high-impedance state, which permits data that is applied on the input/output lines to be clocked into the register. Reading out of the register can be accomplished while the outputs are enabled in any mode. The clear function is synchronous, and a low level at the clear input clears the register on the next low-to-high transition of the clock.

FUNCTION TABLE

MODE	INPUTS							INPUTS/OUTPUTS						OUTPUTS				
	CLR	FUNCTION SELECT		CONTROL		ÇLK	SERIAL		A/Q _A	B/Qg	c/a _c	o/ap	E/Qr	F/Q _E	G/Qc	Н/Ош	Qa	Ω _H ,
		S1	SO	Ğ1 [†]	G2†		SL	SR		•	•	Ĭ	-	,	•		^	-
Clear	L	Х	L	L	L	f	х	Х	L	t.	Ĺ		L	L	L	L.	L	L
	Ļ	L	×	L	L	Ť	×	X	l.	L.	L	L	L	L	Ĺ.	L	L	L
	L	Н	н	х	х	†	x	Х	х	х	×	x	х	×	X	×	L	L
Hold	н	L	L	L	L	×	X	Х	QAO	QBO	©C0	000	QEO	Q _{FQ}	α_{G0}	QHO	QAO	QHO
	н	×	X	L	L	L	×	X	QAO	Ω80	aco	Q00	QE0	QFO	QGO		QAO	
Shift Right	Н	L	Н	Ł	L	Ť	Х	Ĥ	Н	QAn	OBn	QCn	QDn	Q _{En}	Q _{En}	QGn	Н	QGn
	н	L	н	LL.	L	Ť	×	L	L	QAD	QBu	α _{Cn}	a_{Dn}	QEn	Q_{En}	Q _{Gn}	L	α_{Gn}
Shift Left	н	Н	L	L	L	1	н	Х	Qgn	Q _{Cn}	Q _{Dn}	QEn	Q _{En}	QGn	QHn	Н	QBn	Н
	н	н	L	L	L	1	L	X	QBn	Q _{Cn}	αpπ	QΕπ	Q_{Fn}	α _{Gπ}	Q _{Hn}	L	QBn	L
Load	H	Н	н	X	X	1	х	Х	a	b	C	ď	e		9	h	a	h

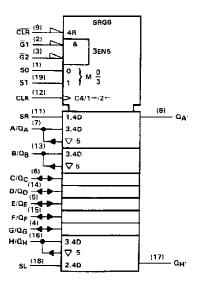
¹When one or both output controls are high the eight input/output terminals are disabled to the high-impedance state: however, sequential operation or clearing of the register is not affected.

a...h e the level of the steady-state input at inputs A through H, respectively. These data are loaded into the flip-flops while the flip-flop outputs are isolated from the input/output terminals.



SN54LS323, SN74LS323 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

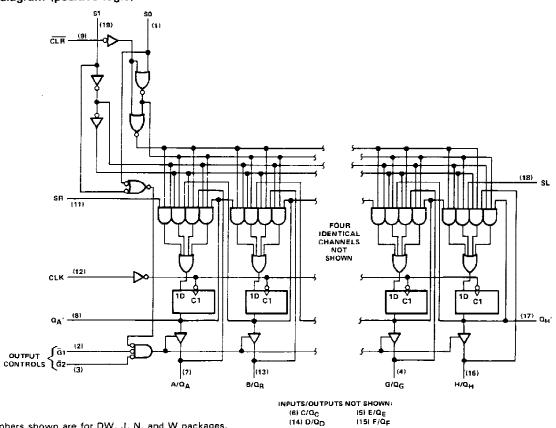
logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, N, and W packages.

logic diagram (positive logic)

Pin numbers shown are for DW, J, N, and W packages.



SN54LS323, SN74LS323 **8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS**

schematics of inputs and outputs, absolute maximum ratings, recommended operating conditions, and electrical characteristics

Same as SN54LS299 and SN74LS299, except t_{SU} (Clear Inactive) does not apply.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{ C}$

PARAMETER †	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP 35	MAX	UNIT
f _{max}			See Note 1	25			
^t PLH	CLK	On car Out	C15 -5 B2 k0		22	33	- ne
[‡] PHL	OER	Q _A , or Q _H ,	C _L = 15 pF, R _L = 2 kΩ		26	39	
^t PLH	CLK	O. shru O.			17	25	ns
^t PHL	CLK	Q _A thru Q _H	0 -45-5 0 -005-0		25	39	
^t PZH	<u>G</u> 1, <u>G</u> 2	Q _A thru Q _H	CL = 45 pF, RL = 665 Ω		14	21	ns
[‡] PZL	d1, d2	CA tille CH			20	30	
^t PHZ	G1, G2	Q _A thru Q _H	C - F - F - B - BEE D		10	20	
tPLZ	31, 02	ч д или ч д	CL=5pF, RL=665Ω		10	15	ns

[†]t_{max} = maximum clock frequency

tpLH = Propagation delay time, low-to-high-level output

tpHL = Propagation delay time, high-to-low-level output

tpzH = Output enable time to high level

tpzL = Output enable time to low level tpHZ = Output disable time from high level

tpLZ = Output disable time from low level

NOTE 1: For testing f_{max}, all outputs are loaded simultaneously, each with C_L and R_L as specified for the propagation times. Load circuits and voltage waveforms are shown in Section 1.

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